

Search Notes



Application/Control No.

10/764,914

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

SIBRAI ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	337	02.25-05	Mr
	393	T	T
	396		
	532		
331	158		
330	86		
331	25	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST See attachment	02.25.05	Mr
Consulted with Tuan Lam	02.25.05	Mr